- Rugged Triple-Diffused Planar Construction
- 10 A Continuous Collector Current
- Operating Characteristics Fully Guaranteed at 100°C
- 1000 Volt Blocking Capability
- 125 W at 25°C Case Temperature

# SOT-93 PACKAGE (TOP VIEW) B 1 C 3

Pin 2 is in electrical contact with the mounting base.

MDTRAA

# absolute maximum ratings at 25°C case temperature (unless otherwise noted)

RATING	SYMBOL	VALUE	UNIT
Collector-base voltage (I <sub>E</sub> = 0)	V <sub>CBO</sub>	850 1000	V
Collector-emitter voltage (V <sub>BE</sub> = 0)	V <sub>CES</sub>	850 1000	V
Collector-emitter voltage (I <sub>B</sub> = 0)	V <sub>CEO</sub>	400 450	V
Emitter-base voltage	V <sub>EBO</sub>	10	V
Continuous collector current	I <sub>C</sub>	10	Α
Peak collector current (see Note 1)	I <sub>CM</sub>	15	Α
Continuous device dissipation at (or below) 25°C case temperature	P <sub>tot</sub>	125	W
Operating junction temperature range	T <sub>j</sub>	-65 to +150	°C
Storage temperature range	T <sub>stg</sub>	-65 to +150	°C

NOTE 1: This value applies for  $t_p \le 10$  ms, duty cycle  $\le 2\%$ .



# TIPL765, TIPL765A NPN SILICON POWER TRANSISTORS

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### electrical characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER		TEST CONDITIONS				MIN	TYP	MAX	UNIT	
V <sub>CEO(sus)</sub>	Collector-emitter sustaining voltage	I <sub>C</sub> = 1	100 mA	L = 25 mH	(see Note 2)	TIPL765 TIPL765A	400 450			V
		V <sub>CE</sub> =	850 V	$V_{BE} = 0$		TIPL765			50	
1	Collector-emitter	$V_{CE} = 1$	1000 V	$V_{BE} = 0$		TIPL765A			50	μA
I <sub>CES</sub>	cut-off current	V <sub>CE</sub> =	850 V	$V_{BE} = 0$	$T_C = 100$ °C	TIPL765			200	μΛ
				$V_{BE} = 0$	$T_C = 100$ °C	TIPL765A			200	
I <sub>CEO</sub>	Collector cut-off		400 V	I <sub>B</sub> = 0		TIPL765			50	μA
-CEO	current	V <sub>CE</sub> =	450 V	$I_B = 0$		TIPL765A			50	
I <sub>EBO</sub>	Emitter cut-off current	V <sub>EB</sub> =	10 V	I <sub>C</sub> = 0					1	mA
h <sub>FE</sub>	Forward current transfer ratio	V <sub>CE</sub> =	5 V	I <sub>C</sub> = 0.5 A	(see Notes 3 ar	nd 4)	15		60	
		I <sub>B</sub> =	0.4 A	$I_C = 2 A$					0.5	
V <sub>CE(sat)</sub>	Collector-emitter	I <sub>B</sub> =	1 A	$I_C = 5 A$	(see Notes 3 ar	nd 4)			1.0	V
* CE(Sal)	saturation voltage	I <sub>B</sub> =	2 A	$I_C = 10 A$					2.5	·
		I <sub>B</sub> =	2 A	$I_{\rm C} = 10  {\rm A}$	$T_C = 100$ °C				5.0	
V <sub>BE(sat)</sub>	- to	I <sub>B</sub> =	0.4 A	$I_C = 2 A$	, , , , ,				1.1	
	Base-emitter	I <sub>B</sub> =	1 A	$I_C = 5 A$	(see Notes 3 ar	id 4)			1.3	V
	saturation voltage	I <sub>B</sub> =	2 A	$I_{C} = 10 \text{ A}$	T 40000				1.7	
		I <sub>B</sub> =	2 A	I <sub>C</sub> = 10 A	T <sub>C</sub> = 100°C				1.6	
f <sub>t</sub>	Current gain bandwidth product	V <sub>CE</sub> =	10 V	$I_{\rm C} = 0.5  {\rm A}$	f = 1 MHz			8		MHz
C <sub>ob</sub>	Output capacitance	V <sub>CB</sub> =	20 V	I <sub>E</sub> = 0	f = 0.1 MHz			150		pF

NOTES: 2. Inductive loop switching measurement.

- 3. These parameters must be measured using pulse techniques,  $t_p$  = 300  $\mu s$ , duty cycle  $\leq$  2%.
- 4. These parameters must be measured using voltage-sensing contacts, separate from the current carrying contacts.

### thermal characteristics

PARAMETER	MIN	TYP	MAX	UNIT
R <sub>6JC</sub> Junction to case thermal resistance			1	°C/W

# inductive-load-switching characteristics at 25°C case temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS †			MIN	TYP	MAX	UNIT
t <sub>sv</sub>	Voltage storage time	I <sub>C</sub> = 10 A V <sub>BE(off)</sub> = -5 V	I <sub>B(on)</sub> = 2 A				2	μs
t <sub>rv</sub>	Voltage rise time			(see Figures 1 and 2)			300	ns
t <sub>fi</sub>	Current fall time						200	ns
t <sub>ti</sub>	Current tail time						50	ns
t <sub>xo</sub>	Cross over time						400	ns
t <sub>sv</sub>	Voltage storage time	I <sub>C</sub> = 10 A V <sub>BE(off)</sub> = -5 V	I <sub>B(on)</sub> = 2 A T <sub>C</sub> = 100°C				3.5	μs
t <sub>rv</sub>	Voltage rise time			(see Figures 1 and 2)			400	ns
t <sub>fi</sub>	Current fall time						300	ns
t <sub>ti</sub>	Current tail time						80	ns
t <sub>xo</sub>	Cross over time						500	ns

 $<sup>^{\</sup>dagger} \ \ \mbox{Voltage and current values shown are nominal; exact values vary slightly with transistor parameters.}$ 

### PRODUCT INFORMATION

### PARAMETER MEASUREMENT INFORMATION

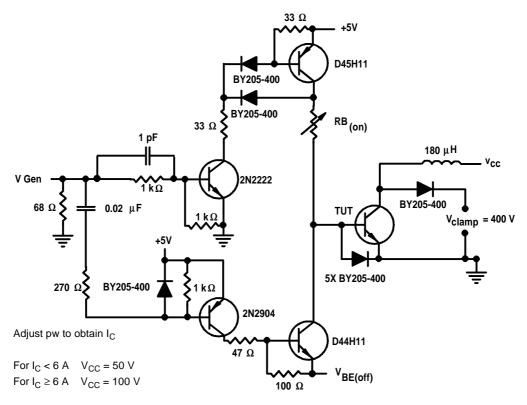
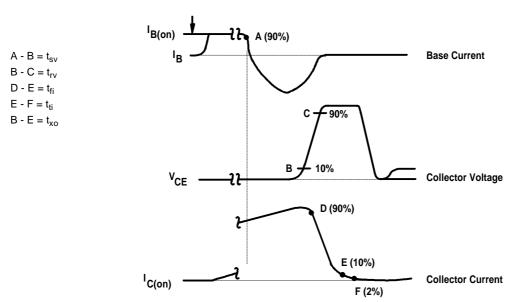


Figure 1. Inductive-Load Switching Test Circuit



NOTES: A. Waveforms are monitored on an oscilloscope with the following characteristics:  $t_r < 15$  ns,  $R_{in} > 10 \Omega$ ,  $C_{in} < 11.5$  pF. B. Resistors must be noninductive types.

Figure 2. Inductive-Load Switching Waveforms



### TYPICAL CHARACTERISTICS

# TYPICAL DC CURRENT GAIN VS COLLECTOR CURRENT TCP765AE TC = 125°C TC = -65°C TC = -65°C TC = -65°C TC = -65°C TC = -65°C

# **COLLECTOR-EMITTER SATURATION VOLTAGE**

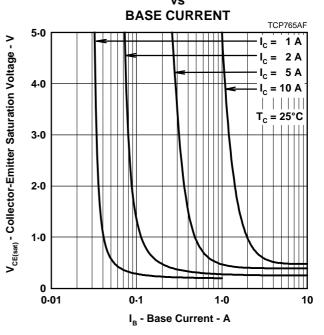
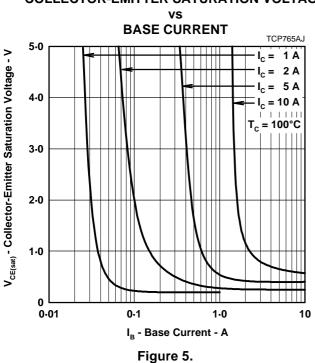


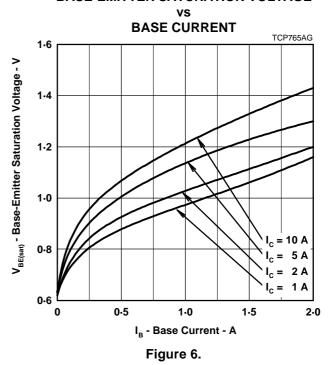
Figure 4.

### **COLLECTOR-EMITTER SATURATION VOLTAGE**

Figure 3.



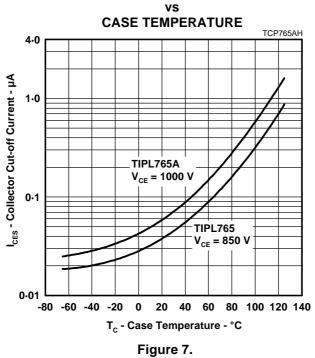
### **BASE-EMITTER SATURATION VOLTAGE**



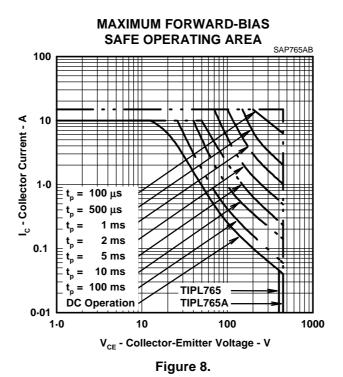
### PRODUCT INFORMATION

### TYPICAL CHARACTERISTICS

# **COLLECTOR CUT-OFF CURRENT**



### **MAXIMUM SAFE OPERATING REGIONS**





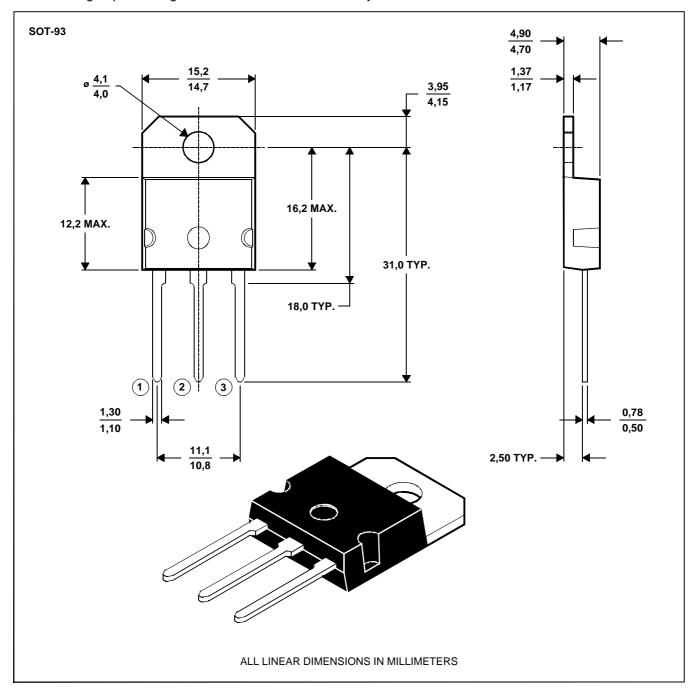
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### **MECHANICAL DATA**

### **SOT-93**

## 3-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



NOTE A: The centre pin is in electrical contact with the mounting tab.

**MDXXAW** 

### PRODUCT INFORMATION

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